DISCRETE SEMICONDUCTORS

DATA SHEET

MAC223A8X Triacs

Product specification

September 2002



NXP Semiconductors Product specification

Triacs MAC223A8X

GENERAL DESCRIPTION

Passivated triac in a full pack, plastic envelope, intended for use in applications requiring high bidirectional transient and blocking voltage capability and high thermal cycling performance. Typical applications include motor control, industrial and domestic lighting, heating and static switching.

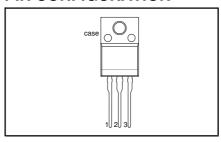
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	UNIT
V _{DRM}	Repetitive peak off-state voltages	600	V
I _{T(RMS)}	RMS on-state current	20	Α
I _{TSM}	Non-repetitive peak on-state	230	Α

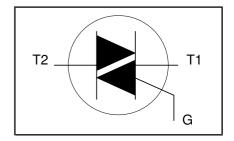
PINNING - SOT186A

PIN	DESCRIPTION			
1	main terminal 1			
2	main terminal 2			
3	gate			
case	isolated			

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DRM}	Repetitive peak off-state voltages		-	600¹	V
$I_{T(RMS)}\\I_{TSM}$	RMS on-state current Non-repetitive peak on-state current	full sine wave; $T_{hs} \le 25$ °C full sine wave; $T_j = 25$ °C prior to surge	-	20	A
l²t dl _⊤ /dt	I ² t for fusing Repetitive rate of rise of on-state current after	t = 16.7 ms t = 10 ms $I_{TM} = 30 \text{ A}; I_{G} = 0.2 \text{ A};$ $dI_{G}/dt = 0.2 \text{ A}/\mu\text{s}$	-	230 180	A A ² s
	triggering	T2+ G+ T2+ G- T2- G- T2- G+	-	50 50 50	A/μs A/μs A/μs
I _{GM} V _{GM} P _{GM}	Peak gate current Peak gate voltage Peak gate power			10 2 5 5	A/μs A V W
P _{G(AV)} T _{stg} T _j	Average gate power Storage temperature Operating junction temperature	over any 20 ms period	-40 -40	0.5 150 125	Ç Ç W

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THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R _{th j-hs}	Thermal resistance junction heatsink Thermal resistance	full or half cycle with heatsink compound without heatsink compound in free air		- - 55	3.85 5.5 -	K/W K/W K/W
,	junction to ambient					

ISOLATION LIMITING VALUE & CHARACTERISTIC

T_{hs} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{isol}	R.M.S. isolation voltage from all three terminals to external heatsink	f = 50-60 Hz; sinusoidal waveform; R.H. ≤ 65% ; clean and dustfree	-	-	2500	V
C _{isol}	Capacitance from T2 to external heatsink	f = 1 MHz	-	10	-	pF

STATIC CHARACTERISTICS

T_i = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
I _{GT}	Gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$					
G1			T2+ G+	-	6	50	mA
			T2+ G-	-	10	50	mA
			T2- G-	-	11	50	mA
			T2- G+	-	23	75	mA
$ \mathbf{l}_{L} $	Latching current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$					_
			T2+ G+	-	8	40	mĄ
			T2+ G-	-	30	60	mĄ.
			T2- G-	-	18	40	mA.
	l.,		T2- G+	-	15	60	mA
I _H	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	To		_	00	A
			T2+	-	7	30	mA
.,	0		T2-	-	12	30	mΑ
$oldsymbol{V}_T$	On-state voltage	$I_{T} = 30 \text{ A}$		-	1.3	1.55	V
V _{GT}	Gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$ $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125$ $V_D = V_{DRM(max)}; T_j = 125 \text{ °C}$	0		0.7	1.5	V
	0#	$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; I_j = 125$, C	0.25	0.4		V
I _D	Off-state leakage current	$V_D = V_{DRM(max)}$; $V_j = 125$ C		-	0.1	0.5	mA

DYNAMIC CHARACTERISTICS

T_i = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
dV _D /dt	Critical rate of rise of	$V_{DM} = 67\% V_{DRM(max)}; T_j = 125 °C;$	100	300	-	V/µs
dV _{com} /dt	Off-state voltage Critical rate of change of	exponential waveform; gate open circuit $V_{DM} = 400 \text{ V}$; $T_j = 95 \text{ °C}$; $I_{T(RMS)} = 25 \text{ A}$;	-	10	-	V/μs
t _{gt}	commutating voltage Gate controlled turn-on time	$ dI_{com}/dt = 9 \text{ A/ms};$ gate open circuit $ I_{TM} = 30 \text{ A};$ $V_D = V_{DRM(max)};$ $ I_G = 0.1 \text{ A};$ $ dI_G/dt = 5 \text{ A/}\mu\text{s}$	-	2	-	μs

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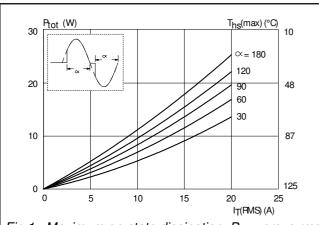


Fig.1. Maximum on-state dissipation, P_{tot} , versus rms on-state current, $I_{T(RMS)}$, where α = conduction angle.

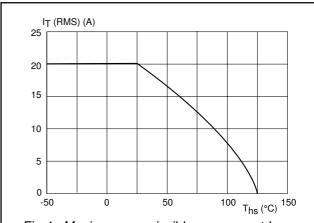


Fig.4. Maximum permissible rms current $I_{\text{T(RMS)}}$, versus heatsink temperature T_{hs} .

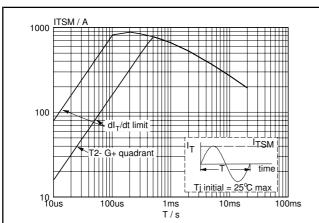


Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus pulse width t_p , for sinusoidal currents, $t_p \le 20$ ms.

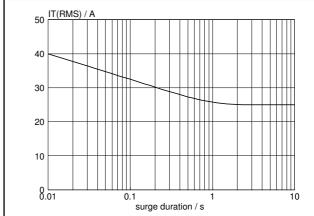


Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, f = 50 Hz; $T_{hs} \le 91 \,^{\circ}\text{C}$.

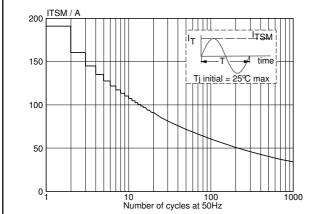


Fig.3. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus number of cycles, for sinusoidal currents, f = 50 Hz.

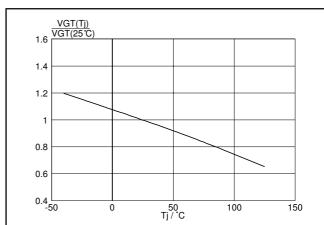
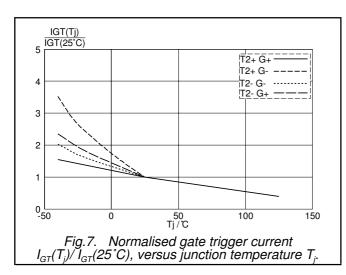
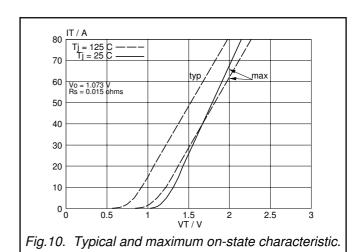


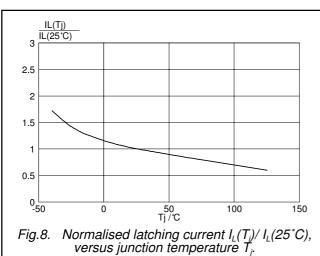
Fig.6. Normalised gate trigger voltage $V_{GT}(T_i)/V_{GT}(25^{\circ}C)$, versus junction temperature T_i .

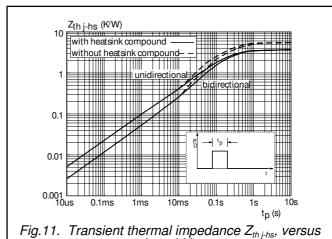
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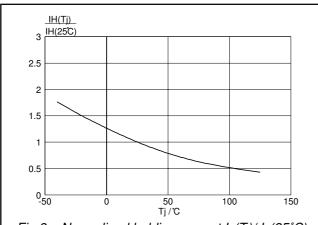


Fig.11. Transient thermal impedance Z_{thj-hs} , versus pulse width t_o.

off-state dV/dt limit

1000 dV/dt (V/us

dlcom/dt = 25 Å/ms

20

100

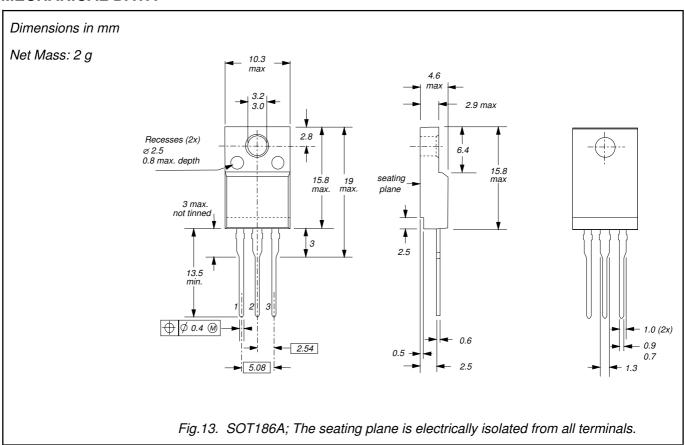
Tj / C Fig.12. Typical commutation dV/dt versus junction temperature, parameter commutation dl_T/dt. The triac should commutate when the dV/dt is below the value on the appropriate curve for pre-commutation dI_{τ}/dt .

Fig.9. Normalised holding current $I_H(T_i)/I_H(25^{\circ}C)$, versus junction temperature T_i .

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MECHANICAL DATA



- Notes
 1. Refer to mounting instructions for F-pack envelopes.
 2. Epoxy meets UL94 V0 at 1/8".

Legal information

DATA SHEET STATUS

DOCUMENT STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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